


<b>Search Notes</b>  	<b>Application/Control No.</b>  10532632	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  Emmanuel Bayard	<b>Art Unit</b>  2611

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	150, 265, 295, 299, 347, 349	8/18/2008	EB

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East	8/18/2008	EB
Inventor search	8/18/2008	EB

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	295, 265	8/18/2008	EB

	/E. B./ Primary Examiner.Art Unit 2611
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